



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **WATANABE, et al.**

Group Art Unit: **2825**

Serial No.: **09/320,271**

Examiner: **Calvin Lee**

Filed: **May 27, 1999**

P.T.O. Confirmation No.: **4409**

For: **SEMICONDUCTOR DEVICE AND FABRICATION METHOD THEREOF**

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 CFR 1.97(b)

Commissioner for Patents
Washington, D.C. 20231

November 18, 2002

Sir:

The attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached Form PTO-1449. One copy of each of these documents is attached.

No fee or certification is required in connection with this Information Disclosure Statement, since it is being submitted prior to the issuance of a first official action on the merits following the **Request for Continued Examination (RCE)** in the above-identified patent application.


The above information is presented so that the Patent and Trademark Office can, in the first instance, determine any materiality thereof to the claimed invention. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the documents cited in the attached Form PTO-1449 be made of record therein and appear on the first page of any patent to issue therefrom.

A list of related copending application is also attached hereto. The cited references were made of record in the related copending application.

The Commissioner is authorized to charge our Deposit Account No. 01-2340 for any fee which is deemed by the Patent and Trademark Office to be required to effect consideration of this statement.

Respectfully submitted,

ARMSTRONG, WESTERMAN & HATTORI, LLP


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Atty. Docket No. 990559
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PATENT TRADEMARK OFFICE

Enclosures: PTO-1449
References
Related Copending Applications



2825

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For: **SEMICONDUCTOR DEVICE AND FABRICATION METHOD
THEREOF**

Attorney Docket No.: **990559**

Customer Number: **38834**

REQUEST FOR RETURN OF FORM PTO-1449

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

March 26, 2004

Sir:

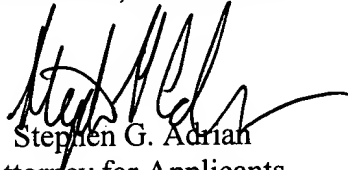
Applicants filed an Information Disclosure Statement (IDS) on November 18, 2002. The IDS contained seven sheets of Form PTO-1449. Only two of these sheets were returned. A copy of this IDS is attached hereto along with the five sheets which were not marked to indicate that the references were considered. In addition, that IDS contained a sheet identifying related copending applications.

Applicant respectfully requests that the Examiner return a copy of the Forms PTO-1449 that accompany the Information Disclosure Statement, marked to indicate that the references listed therein have been considered by the Office.

The Examiner is encouraged to telephone the undersigned if the Examiner has any questions concerning this Request.

Respectfully submitted,

WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP

A handwritten signature in black ink, appearing to read "Stephen G. Adrian", is written over the printed name.

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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

990559

SERIAL NO.

09/320,271

LIST OF REFERENCES CITED BY APPLICANT

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WATANABE et al.

FILING DATE

May 27, 1999

GROUP

2825

(Use several sheets if necessary)

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| | AA | 5,024,723 | 06/18/91 | Goesele, et al. | 156 | 628 | |
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| CT | "Lithography I: Optical Resist Material and Process Technology," (pp. 441). |
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| CX | Lai-Juh Chen, et al., "Flourine-Implanted Treatment (FIT) SOG for the Non-Etchback Intermetal Dielectric," IEEE VMIC Conference, June 7-8, 1994, pp. 81-86. |
| CY | Moriya, et al., "Modification Effects in Ion-Implanted SiO ₂ Spin-on-Glass," Journal of Electrochem. Soc., Vol. 140, No. 5, May 1993, pp. 1442-1450. |
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| DB | Doki, et al., "Mositure-Blocking Mechanism of ECR-Plasma," IEEE VMIC Conference, June 7-8, 1994, pp. 235-239. |
| DC | Shimokawa, et al., "Suppression of MOSFET Hot Carrier Degradation by P-SiO Underlayer," The Institute of Electronics, Information and Communication Engineers, Techninal Report of IEICE, SDM92-133 (1992-12), pp. 89-94. |
| DD | Murase, et al., "Dielectric Constant of Silicon Dioxide Deposited by Atospheric-Pressure Chemical Vapor Deposition Using Tetraethylorthosilicate and Ozone," Japanese Journal of Applied Physics, Vol. 33, (1994), pp. 1385-1389. |

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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| _____ | AR | Wolf et al. "Silicon Processing for the VLSI Era: Volume I - Process Technology," "Lattice Press, 1986 p. 441. |
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| _____ | AX | Office Action of Japanese Application No. 07-227294. |
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| Date Considered | | |

Related Copending Applications

| <u>Application No.</u> | <u>Filing Date</u> | <u>Attorney Docket No.</u> | <u>Status</u> |
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| 08/921,250 | 8/29/97 | 970813 | Pending |
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